IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Pa	atent A	pplica	ation of:						
Je-Hyou	ung R`	YU, e	t al.						
Applicat	tion N	o.:		Group Art Unit:					
Filed: A	April 14	4, 200	4	Examiner:					
For:	INSPE	CTIN	G APPARATUS FOR SEMICON	NDUCTOR DEVICE					
	INFORMATION DISCLOSURE STATEMENT								
Commis PO Box Alexano	1450		Patents 13-1450						
Sir:									
provided the subj	d certa ject U.	ain info S. pa	ormation which the Examiner ma	ovisions of 37 CFR § 1.56, there is hereby ay consider material to the examination of that the Examiner make this information of the subject application.					
	1.	Encl	osures accompanying this Inforr	mation Disclosure Statement are:					
	1b. 1c. 1d.		application or a PCT Internation English language translation (c each non-English language pul Explanations of Relevancy of F	earch report(s) from a counterpart foreign nal Search Report. complete or relevant portion(s)) attached to					
2	. 🖂			a concise explanation of what is presently each non-English language publication is					
			enclosed "English-language ve indicates the degree of relevan 609, Minimum Requirements for A(3): Concise Explanation of R Feb. 2000.)	s 2a, 2b, 2c and/or 2d) sh language publications were cited on the rsion of the search report or action which are found by the foreign office. (See MPEP or an Information Disclosure Statement, Part televance, pp. 600-100 to 600-101, Rev. 1,					
	20.	\boxtimes	set forth in the application.						

	c. □ d. ⊠	satisfied because an Eng portion(s)) is attached to enclosed as Attachment	each nor	n-English language p	
t (to be, ma (other th	ssion is made that the info aterial to patentability nor an search report(s) from a onal Search Report, if sub	a represe a counter	entation that a search part foreign application	n has been made on or a PCT
				Respectfully submit	ted,
				STAAS & HALSEY	LLP
	ork Ave n, D.C. 2 (202) 43	34-1500	Ву:	Gene M. Garner II Registration No. 34	,172

FORM P	TO-1	449
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

E 1572.1242

APPLICATION NO.

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Je-Hyoung RYU, et al.

FILING DATE

April 14, 2004

FIRST NAMED INVENTOR

GROUP ART UNIT

U.S. PATENT DOCUMENTS

0.5.1 ATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA				i		
	АВ						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

			711 EITI DOCUMENTO				
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANS YES	NO
AG	KR 2003-6195	1/23/03	Korea			Х	
АН							
Al						-	
AJ							
AK							
 AL							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

		TRANSI YES	ATION NO
AM	Korean Utility Model #20-0157983		x
AN			
AO			

EXAMINER

DATE CONSIDERED

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ATTACHMENT 1(e)

EXPLANATIONS OF RELEVANCY OF REFERENCES

ATTORNEY DOCKET NO.	APPLICATION NO.					
ATTORNET DOCKET NO.	APPLICATION NO.					
1572.1242						
CIDOTALIAN CO INDICATOR						
FIRST NAMED INVENTOR						
Je-Hyoung RYU, et al.						
FILING DATE	GROUP ART UNIT					
April 14, 2004						

Reference AG (KR 2003-6195) is entitled "Semiconductor Element Testing Apparatus".